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AMENDMENTS TO THE CLAIMS:

The following listing of claims replaces all prior versions, and all prior listings,

of claims in the application.

LISTING OF CLAIMS:

. (Currently amended) A circuit connecting material which is used to

connect a first circuit member in which first circuit electrodes and first insulating

layers are formed adjacent to each other on the main surface of a first circuit board,

and a second circuit member in which second circuit electrodes and second

insulating layers are formed adjacent to each other on the main surface of a second

circuit board, with at least some of said insulating layers being formed such that

these layers are thicker than said circuit electrodes on the basis of said main surface

in at least one of said first and second circuit members,

wherein said material contains a bonding agent composition and conductive

particles which have a mean particle size of 1 µm or greater but less than 10 µm,

and a hardness of 1.961 to 6.865 GPa; and

said material exhibits, when subjected to a curing treatment, a storage elastic

modulus module of 0.5 to 3 GPa at 40°C, and a mean coefficient of thermal

expansion of 30 to 200 ppm/°C at from 25°C to 100°C.

2. (Original) The circuit connecting material according to claim 1, wherein

said conductive particles comprise a core body made of an organic polymer, and a

metal layer made of copper, nickel, a nickel alloy, silver or a silver alloy which is

formed on the surface of said core body, and the thickness of said metal layer is 50

to 170 nm.

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(Currently amended) The circuit connecting material according to claim 1

or 2, wherein said conductive particles comprise an outermost layer made of gold or

palladium, and the thickness of said outermost layer is 15 to 70 nm.

4. (Currently amended) The circuit connecting material according to claim 1

any one of claims 1-to 3, wherein said bonding agent composition contains an epoxy

resin and a latent curing agent for said epoxy resin.

5. (Currently amended) The circuit connecting material according to claim 1

any one of claims 1 to 3, wherein said bonding agent composition contains a radical-

polymerizable substance, and a curing agent which generates free radicals when

heated.

6. (Currently amended) The circuit connecting material according to claim 1

any one of claims 1 to 5, wherein the glass transition temperature is 60 to 200°C as

a result of the curing treatment.

7. (Currently amended) The circuit connecting material according to claim 1

any one of claims 1 to 6, wherein the material further contains a film forming

material.

8. (Original) The circuit connecting material according to claim 7, wherein

said film forming material is a phenoxy resin.

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9. (Currently amended) A film-form circuit connecting material which is

formed by forming the circuit connecting material according to claim 1 any one of

claims 1 to 8 into shape of a film.

(Currently amended) A circuit member connecting structure comprising:

a first circuit member in which first circuit electrodes and first insulating layers

are formed adjacent to each other on the main surface of a first circuit board;

a second circuit member in which second circuit electrodes and second

insulating layers are formed adjacent to each other on the main surface of a second

circuit board; and

a circuit connecting member which is disposed between the main surface of

said first circuit member and the main surface of said second circuit member for

connecting said first and second circuit members to each other;

at least some of said insulating layers being formed so that these layers are

thicker than said circuit electrodes on the basis of the main surface of the circuit

board in at least one of said first and second circuit members.

wherein said circuit connecting member contains an insulating substance and

conductive particles that have a mean particle size of 1 µm or greater but less than

10 μm, and a hardness of 1.961 to 6.865 GPa,

the storage elastic modulus module of said circuit connecting member at 40°C

is 0.5 to 3 GPa, and the mean coefficient of thermal expansion of this member from

25°C to 100°C is 30 to 200 ppm/°C, and

said first circuit electrodes and said second circuit electrodes are electrically

connected via said conductive particles.

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11. (Original) The circuit member connecting structure according to claim 10,

wherein said conductive particles comprise a core body made of an organic polymer,

and a metal layer made of copper, nickel, a nickel alloy, silver or a silver alloy which

is formed on the surface of said core body, and the thickness of said metal layer is

50 to 170 nm.

12. (Currently amended) The circuit member connecting structure according

to claim 10 or 11, wherein said conductive particles comprise an outermost layer

made of gold or palladium, and the thickness of said outermost layer is 15 to 70 nm.

13. (Currently amended) The circuit member connecting structure according

to claim 10 any one of claims 10 to 12, wherein, in at least one the circuit member

member(s) in which at least some of said insulating layers are formed with a greater

thickness than said circuit electrodes on the basis of the main surface of said circuit

board, the difference between the thickness of said at least some of the insulating

layers and the thickness of the circuit electrodes is 50 to 600 nm.

14. (Currently amended) The circuit member connecting structure according

to claim 10 any one of claims 10 to 13, wherein the glass transition temperature of

said circuit member is 60 to 200°C.

15. (Currently amended) The circuit member connecting structure according

to claim 10 any one of claims 10 to 14, wherein said insulating layers are constructed

from one of an organic insulating substance, silicon dioxide and silicon nitride.

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16. (Currently amended) The circuit member connecting structure according

to claim 10 any one of claims 10 to 15, wherein, in at least one of said first and

second circuit members, the surface area of said circuit electrodes is 15,000 µm2 or

less, and the mean number of conductive particles between said first circuit

electrodes and said second circuit electrodes is 3 or greater[[,]].

17. (Currently amended) The circuit member connecting structure according

to claim 10 any one of claims 10 to 16, wherein, in at least one of said first and

second circuit members, said circuit electrodes have a surface layer constructed

from gold, silver, tin, a metal of the platinum group or indium tin oxide.

18. (Currently amended) The circuit member connecting structure according

to claim 10 any one of claims 10 to 17, wherein, in at least one of said first and

second circuit members, said circuit board is constructed from an organic insulating

substance, glass or silicon.

19. (Original) A method for manufacturing a circuit member connecting

structure which comprises a first circuit member in which first circuit electrodes and

first insulating layers are formed adjacent to each other on the main surface of a first

circuit board, a second circuit member in which second circuit electrodes and second

insulating layers are formed adjacent to each other on the main surface of a second

circuit board, and a circuit connecting member which is disposed between the main

surface of said first circuit member and the main surface of said second circuit

member for connecting said first and second circuit members to each other, at least

some of said insulating layers being formed so that these layers are thicker than said

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circuit electrodes on the basis of the main surface of the circuit board in at least one

of said first and second circuit members.

said method comprising the steps of:

interposing the film-form circuit connecting material according to claim 9

between the main surface of said first circuit board and the main surface of said

second circuit board, and

curing said circuit connecting material by the application of heat and pressure

via said first and second circuit members for thereby connecting said first circuit

member and said second circuit member, so that said first circuit electrodes and said

second circuit electrodes are electrically connected via said conductive particles.